

Notice of References Cited

Application/Control No.

09/944,289

Applicant(s)/Patent Under

Reexamination

WEIER ET AL.

Examiner

Tae H Yoon

Art Unit

1714

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,245,070	01-1981	Kemp, Thomas	526/75
	B	US-5,094,998	03-1992	Hoshino et al.	503/207
	C	US-6,028,135	02-2000	Keller et al.	524/458
	D	US-6,245,848	06-2001	Espiard et al.	524/419
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.